

| | | | |
|-----------------------------------|-------------------------|---|-------------|
| Notice of References Cited | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | 09/839,264 | SAITO ET AL. | |
| Examiner | Tai V Nguyen | Art Unit | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-4,805,074 | 02-1989 | Harakawa et al. | 361/525 |
| | B | US-5,140,502 | 08-1992 | Kudoh et al. | 361/540 |
| | C | US-5,212,402 | 05-1993 | Higgins, III, Leo M. | 257/532 |
| | D | US-5,377,073 | 12-1994 | Fukaumi et al. | 361/540 |
| | E | US-5,062,025 | 10-1991 | Verhoeven et al. | 361/509 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|----------------|----------------|
| | N | JP-403109712A | 05-1991 | JP | Imanishi et al | H01G009/05 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.